

Qualification Results Summary of LT8650S at Vanguard International Semiconductor

QUALIFICATION STATUS – LT8650S 32L LQFN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	1*231	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	1*77	Pass
Temperature Cycling (TC)*	JEDEC <i>JESD22-A104</i>	1*77	Pass
Unbiased Highly Accelerated Stress Test (UHAST)*	JEDEC <i>JESD22-A102</i>	1*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1*45	Pass
Latch-Up	JEDEC <i>JESD78</i>	> ±100mA	Pass
Electrostatic Discharge <i>Human Body Model</i>	ESDA/JEDEC <i>JS-001</i>	3/voltage	Pass 4000V
Electrostatic Discharge <i>Field-Induced Charged Device Model</i>	JEDEC <i>JESD22-C101</i>	3/voltage	Pass 2000V

*Preconditioned per JEDEC/IPC J-STD-020

Qualification Results Summary of LT8650S at Vanguard International Semiconductor

QUALIFICATION STATUS – LT8650SP 32L LQFN			
TEST	SPECIFICATION	SAMPLE SIZE	RESULTS
High Temperature Operating Life (HTOL)	JEDEC <i>JESD22-A108</i>	3*77	Pass
Solder Heat Resistance (SHR)*	JEDEC/IPC <i>J-STD-020</i>	3*231	Pass
Highly Accelerated Stress Test (HAST)*	JEDEC <i>JESD22-A110</i>	3*77	Pass
Temperature Cycling (TC)*	JEDEC <i>JESD22-A104</i>	2*77	Pass
Unbiased Highly Accelerated Stress Test (UHAST)*	JEDEC <i>JESD22-A102</i>	3*77	Pass
High Temperature Storage Life (HTSL)	JEDEC <i>JESD22-A103</i>	1*45	Pass

*Preconditioned per JEDEC/IPC J-STD-020